

# CMOS QUAD LOW-TO-HIGH VOLTAGE SHIFTER

Check for Samples: CD40109B-Q1

#### **FEATURES**

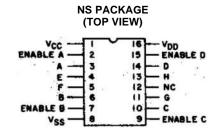
- Qualified for Automotive Applications
- Independent of Power Supply Sequence Considerations
  - V<sub>CC</sub> Can Exceed V<sub>DD</sub>
  - Input Signals can Exceed Both V<sub>CC</sub> and V<sub>DD</sub>
- Up and Down Level-Shifting Capability
- Three-State Outputs With Separate Enable Controls
- Standardized Symmetrical Output Characteristics
- 100% Tested for Quiescent Current at 20 V
- Maximum Input Current:
  - 1 µA at 18 V Over Full
     Package-Temperature Range
  - 100 nA at 18 V and 25°C
- Noise Margin (Full Package-Temperature Range):
  - 1 V at  $V_{CC} = 5 \text{ V}, V_{DD} = 10 \text{ V}$
  - 2 V at  $V_{CC} = 10 \text{ V}, V_{DD} = 15 \text{ V}$
- 5-V, 10-V, and 15-V Parametric Ratings
- Meets All Requirements of JEDEC Tentative Standard No. 13B, "Standard specifications for

**Description of 'B' Series CMOS Devices"** 

 Latch-Up Performance Meets 50 mA per JESD 78, Class I

### **APPLICATIONS**

- High-or-Low Level-Shifting With Three-State Outputs for Unidirectional or Bidirectional Bussing
- Isolation of Logic Subsystem Using Separate Power Supplies from Supply Sequencing, Supply Loss, and Supply Regulation Considerations



#### DESCRIPTION

CD40109B contains four low-to-high-voltage level-shifting circuits. Each circuit will shift a low-voltage digital-logic input signal (A, B, C, D) with logical  $1 = V_{CC}$  and logical  $0 = V_{SS}$  to a high-voltage output signal (E, F, G, H) with logical  $1 = V_{DD}$  and logical  $0 = V_{SS}$ .

The RCA-CD40109, unlike other low-to-high level-shifting circuits, does not require the presence of the high-voltage supply ( $V_{DD}$ ) before the application of either the low-voltage supply ( $V_{CC}$ ) or the input signals. There are no restrictions on the sequence of application of  $V_{DD}$ ,  $V_{CC}$ , or the input signals. In addition, with one exception there are no restrictions on the relative magnitudes of the supply voltages or input signals within the device maximum ratings, provided that the input signal swings between  $V_{SS}$  and at least 0.7  $V_{CC}$ ;  $V_{CC}$  may exceed  $V_{DD}$ , and input signals may exceed  $V_{CC}$  and  $V_{DD}$ . When operated in the mode  $V_{CC} > V_{DD}$ , the CD40109 will operate as a high-to-low level-shifter.

The CD40109 also features individual three-state output capability. A low level on any of the separately enabled three-state output controls produces a high-impedance state in the corresponding output.

### ORDERING INFORMATION(1)

T <sub>A</sub>	PACK	AGE <sup>(2)</sup>	ORDERABLE PART NUMBER	TOP-SIDE MARKING
–40°C to 125°C	SOIC - NS	Reel of 2000	CD40109BQNSRQ1	CD40109BQ

<sup>(1)</sup> For the most current package and ordering information, see the Package Option Addendum at the end of this document, or see the TI web site at www.ti.com.

(2) Package drawings, thermal data, and symbolization are available at www.ti.com/packaging.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.





This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

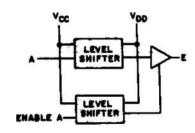
ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

# TRUTH TABLE(1)

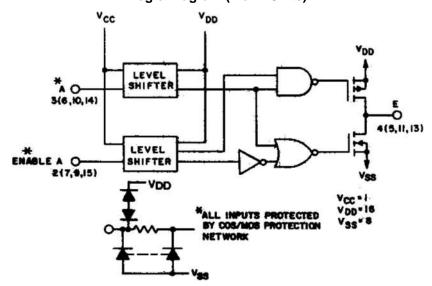
INP	UTS	OUTPUTS
A, B, C, D	ENABLE A, B, C, D	E, F, G, H
0	1	0
1	1	1
X	0	Z

(1)  $0 = V_{SS}$ ,  $1 = V_{CC}$  at inputs and  $V_{DD}$  at outputs, X = Don't care, Z = High impedance

### Functional Diagram (1 of 4 Units)



# Logic Diagram (1 of 4 Units)





# **ABSOLUTE MAXIMUM RATINGS**(1)

over operating free-air temperature range (unless otherwise noted)

			VALUE	UNIT
$V_{DD}$	DC supply voltage range	Voltages referenced to V <sub>SS</sub> terminal	-0.5 to +20	V
	Output voltage range	All outputs	-0.5 to V <sub>DD</sub> + 0.5	V
	DC input current	Any one input	±10	mA
		$T_A = -40^{\circ}C \text{ to } + 100^{\circ}C$	500	mW
$P_D$	Power dissipation per package	T <sub>A</sub> = 100°C to + 125°C	Derate linearly at 12 mW/°C to 200 mW	
	Device dissipation per output tra (for T <sub>A</sub> = full package-temperati		100	mW
T <sub>A</sub>	Operating-temperature range		-40 to +125	°C
T <sub>stg</sub>	Storage temperature range		-65 to +150	°C
	Latch-Up Performance per JES	D 78, Class I	50	mA

<sup>(1)</sup> Stresses beyond those listed under absolute maximum ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under recommended operating conditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

### RECOMMENDED OPERATING CONDITIONS

	MIN	MAX	UNIT
V <sub>DD</sub> Supply-voltage range (for T <sub>A</sub> = full package-temperature range)	3	18	V

### STATIC ELECTRICAL CHARACTERISTICS

		C	ONDITIO	NS		LIMITS A	T INDICA	TED TEM	PERATU	RES (°C)		
	PARAMETER	Vo	V <sub>IN</sub>	$V_{DD}$	-40	+85	+125		+25		UNIT	
		(V)	(V)	(V)	40	+03	TIZJ	MIN	TYP	MAX	ONII	
			0, 5	5	1	30	30		0.02	1		
I Mov	Outcoant device current		0, 10	10	2	60	60		0.02	2		
I <sub>DD</sub> Max	Quiescent device current		0, 15	15	4	120	120		0.02	4	μA	
			0, 20	20	20	600	600		0.04	20		
		0.4	0, 5	5	0.61	0.42	0.36	0.51	1			
I <sub>OL</sub> Min	Output low (sink) current	0.5	0, 10	10	1.5	1.1	0.9	1.3	2.6			
		1.5	0, 15	15	4	2.8	2.4	3.4	6.8			
		4.6	0, 5	5	-0.61	-0.42	-0.36	-0.51	-1		mA	
I Min	Output high (source) current	2.5	0, 5	5	-1.8	-1.3	-1.15	-1.6	-3.2			
I <sub>OH</sub> Min		9.5	0, 10	10	-1.5	-1.1	-0.9	-1.3	-2.6			
		13.5	0, 15	15	-4	-2.8	-2.4	-3.4	-6.8			
			0, 5	5	0.05			0	0.05			
V <sub>OL</sub> Max	Output voltage: low-level		0, 10	10		0.05			0	0.05		
			0, 15	15		0.05			0	0.05		
			0, 5	5		4.95		4.95	5		V	
V <sub>OH</sub> Min	Output voltage: high-level		0, 10	10		9.95		9.95	10			
			0, 15	15		14.95		14.95	15			
I <sub>IN</sub> Max	Input current		0, 18	18	±0.1	±1	±1		±10 <sup>-5</sup>	±0.1	μΑ	
I <sub>OUT</sub> Max			0, 18	18	±0.4	±12	±12		±10 <sup>-4</sup>	±0.4	μA	
		1, 9	5	10		1.5				1.5		
V <sub>IL</sub> Max	Input low voltage	1.5, 13.5	10	15		3				3	\ /	
		1, 9	5	10		3.5		3.5			V	
V <sub>IH</sub> Min	Input high voltage	1.5, 13.5	10	15		7		7				



### **DYNAMIC ELECTRICAL CHARACTERISTICS**

 $T_A$  = 25°C, Input  $t_r/t_f$  = 20 ns,  $C_L$  = 50 pF,  $R_L$  = 200 k $\Omega$  (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	SHIFTING MODE	V <sub>CC</sub> (V)	V <sub>DD</sub> (V)	MIN	MAX	UNIT
				5	10	300	600	
Propagation delay time.			L – H	5	15	220	440	
	Propagation delay time, high-to-low level, data input to output			10	15	180	360	
t <sub>PHL</sub>				10	5	250	500	ns
	, ,		H – L	15	5	250	500	
				15	10	120	240	
				5	10	130	260	
			L – H	5	15	120	240	
	Propagation delay time,			10	15	70	140	
t <sub>PLH</sub>	low-to-high level, data input to output			10	5	230	460	ns
	, ,		H – L	15	5	230	460	
				15	10	80	160	
				5	10	60	120	
	Danie and Care delay Care		L – H	5	15	75	150	
Propagation delay time, 3-state disable, delay,	D 410		10	15	35	70		
t <sub>PHZ</sub>	output high to high	$R_L = 1 k\Omega$		10	5	200	400	ns
	impedance		H – L	15	5	200	400	
				15	10	40	80	
				5	10	370	740	
Dranagation dalou			L – H	5	15	300	600	ns
	Propagation delay time, 3-state disable, delay,			10	15	250	500	
t <sub>PLZ</sub>	output low to high	$R_L = 1 k\Omega$		10	5	250	500	
	impedance		H – L	15	5	250	500	
				15	10	130	260	
				5	10	320	640	
			L – H	5	15	230	460	
	Propagation delay time, 3-state disable, delay,			10	15	180	360	
t <sub>PZH</sub>	output high impedance	$R_L = 1 k\Omega$		10	5	300	600	ns
	to high		H – L	15	5	300	600	
				15	10	130	260	
				5	10	100	200	
			L – H	5	15	80	160	
	Propagation delay time, 3-state disable, delay,			10	15	40	80	
$t_{PZL}$	output high impedance	$R_L = 1 \text{ k}\Omega$		10	5	200	400	ns
	to low		H – L	15	5	200	400	
				15	10	40	80	
				5	10	50	100	
			L – H	5	15	40	80	
				10	15	40	80	
t <sub>THL</sub> , t <sub>TLH</sub>	Transition time			10	5	100	200	ns
			H – L	15	5	100	200	
			_	15	10	50	100	
C <sub>i</sub>	Input capacitance				input	5	7.5	pF



#### TYPICAL CHARACTERISTICS

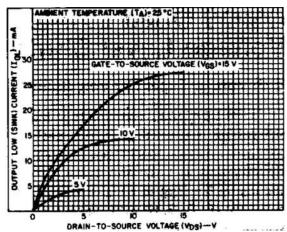


Figure 1. Typical Output Low (Sink) Current Characteristics

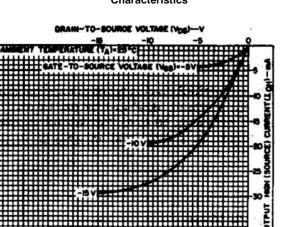


Figure 3. Typical Output High (Source) Current Characteristics

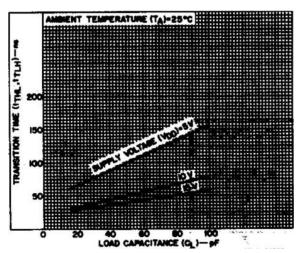


Figure 5. Typical Transition Time as a Function of Load Capacitance

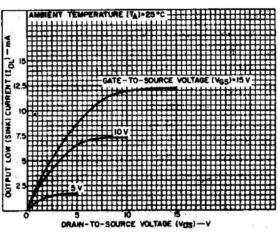


Figure 2. Minimum Output Low (Sink) Current Characteristics

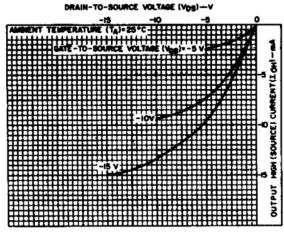


Figure 4. Minimum Output High (Source) Current Characteristics

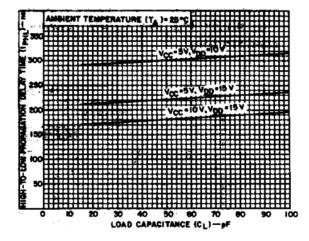


Figure 6. Typical High-to-Low Propagation Delay Time as a Function of Load Capacitance



### TYPICAL CHARACTERISTICS (continued)

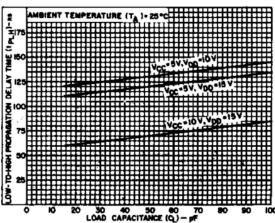


Figure 7. Typical Low-to-High Propagation Delay Time as a Function of Load Capacitance

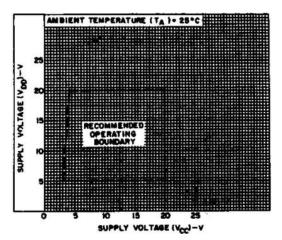


Figure 9. High-Level Supply Voltage vs Low-Level Supply Voltage

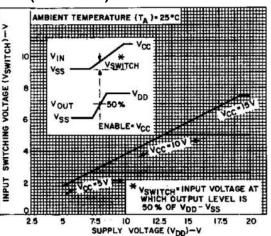


Figure 8. Typical Input Switching as a Function of High-Level Supply Voltage

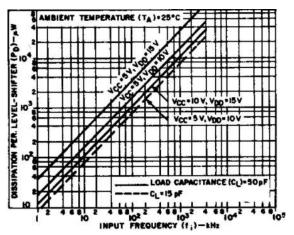


Figure 10. Typical Dynamic Power Dissipation as a Function of Input Frequency



### PARAMETER MEASUREMENT INFORMATION

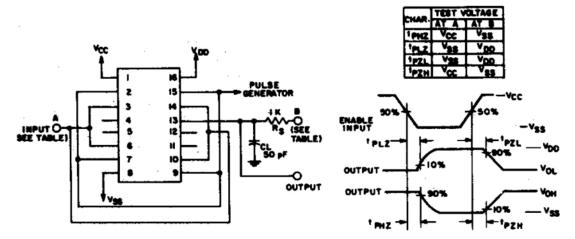


Figure 11. Output Enable Delay Times Test Circuit and Waveforms

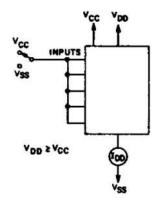
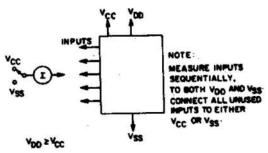


Figure 12. Quiescent Device Current Test Circuit



**Figure 14. Input Current Test Circuit** 

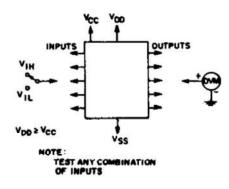


Figure 13. Input Voltage Test Circuit

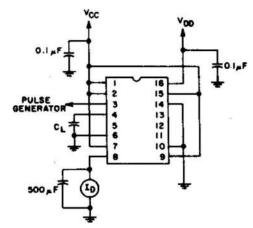
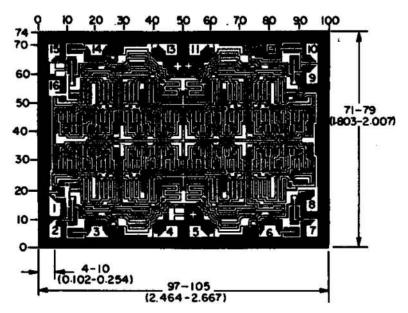


Figure 15. Dynamic Power Dissipation Test Circuit





Note: Dimensions in parentheses are in millimeters and are derived from the basic inch dimensions as indicated. Grid graduations are in mils  $(10^{-3})$  inch).

Figure 16. Dimensions and Pad Layout







10-Dec-2020

#### **PACKAGING INFORMATION**

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
CD40109BQNSRQ1	ACTIVE	SO	NS	16	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	CD40109BQ	Samples

(1) The marketing status values are defined as follows:

**ACTIVE:** Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

**Green:** TI defines "Green" to mean the content of Chlorine (Cl) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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#### OTHER QUALIFIED VERSIONS OF CD40109B-Q1:



# **PACKAGE OPTION ADDENDUM**

10-Dec-2020

Catalog: CD40109B

Military: CD40109B-MIL

NOTE: Qualified Version Definitions:

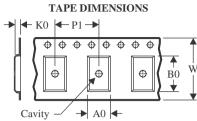
- Catalog TI's standard catalog product
- Military QML certified for Military and Defense Applications

# **PACKAGE MATERIALS INFORMATION**

www.ti.com 3-Jun-2022

### TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

### QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



#### \*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CD40109BQNSRQ1	SO	NS	16	2000	330.0	16.4	8.2	10.5	2.5	12.0	16.0	Q1

# **PACKAGE MATERIALS INFORMATION**

www.ti.com 3-Jun-2022



### \*All dimensions are nominal

Ì	Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
ı	CD40109BQNSRQ1	SO	NS	16	2000	356.0	356.0	35.0

# **MECHANICAL DATA**

# NS (R-PDSO-G\*\*)

# 14-PINS SHOWN

### PLASTIC SMALL-OUTLINE PACKAGE



NOTES:

- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion, not to exceed 0,15.





SOP



#### NOTES:

- 1. All linear dimensions are in millimeters. Dimensions in parenthesis are for reference only. Dimensioning and tolerancing
- per ASME Y14.5M.

  2. This drawing is subject to change without notice.

  3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 mm, per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm, per side.



SOF



### NOTES: (continued)

5. Publication IPC-7351 may have alternate designs.

6. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SOP



#### NOTES: (continued)

- 7. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 8. Board assembly site may have different recommendations for stencil design.



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